Search No	tes

Application/Control No.	Applicant(s)/Patent under Reexamination NOZU, TAKASHI	
Wannana Chan	2624	

SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST (USPAT, US-PUPUB, EPO, JPO, DERWENT, IBM_TDB, USOCR, FPRS) - See search history printout.	10/30/66	un	
IEEE Xplore - See search condition and result printout.	11/1/06.	mi	
EAST (updated)	5/14/07	are	
EAST Supported	11/28/07	ar	